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APPLICATION NO). F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/787,234		02/27/2004	In-Kwang Yu	6192.0359.US	4801		
23345	7590	06/07/2005		EXAMINER			
MCGUIR	EWOODS	S, LLP	CHEN, WEN YING PATTY				
1750 TYS SUITE 18	ONS BLVI 00)	ART UNIT	PAPER NUMBER			
MCLEAN	, VA 2210	02	2871				
					DATE MAILED: 06/07/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

					1/2			
		Applicat	ion No.	Applicant(s)				
		10/787,2	234	YU, IN-KWANG				
Office Action Summary		Examine	er	Art Unit	-			
		Wen-Yin	g P. Chen	2871				
Period fo	The MAILING DATE of this commun or Reply	nication appears on th	e cover sheet with ti	he correspondence add	ress			
THE - Exte after - If the - If NO - Failt Any	ORTENED STATUTORY PERIOD F MAILING DATE OF THIS COMMUN nsions of time may be available under the provisions SIX (6) MONTHS from the mailing date of this come period for reply specified above is less than thirty (3 period for reply is specified above, the maximum so tre to reply within the set or extended period for reply reply received by the Office later than three months ed patent term adjustment. See 37 CFR 1.704(b).	ICATION. s of 37 CFR 1.136(a). In no e munication. 30) days, a reply within the sta tatutory period will apply and v y will, by statute, cause the ap	vent, however, may a reply to atutory minimum of thirty (30) will expire SIX (6) MONTHS oplication to become ABAND	pe timely filed) days will be considered timely, from the mailing date of this con ONED (35 U.S.C. § 133).				
Status								
1)	Responsive to communication(s) file	ed on						
•		2b)⊠ This action is	non-final.					
3) 🗌	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
·	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims							
4)🖂	Claim(s) 1-20 is/are pending in the	application.						
	4a) Of the above claim(s) is/are withdrawn from consideration.							
5)□	Claim(s) is/are allowed.							
6)⊠	Claim(s) <u>1-20</u> is/are rejected.							
7)	Claim(s) is/are objected to.							
8)[Claim(s) are subject to restriction and/or election requirement.							
Applicat	ion Papers							
9)[The specification is objected to by the	ne Examiner.						
10)	10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.							
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
	Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).							
11)	The oath or declaration is objected t	o by the Examiner. N	lote the attached Of	fice Action or form PT0	O-152.			
Priority	under 35 U.S.C. § 119							
a)	Acknowledgment is made of a claim All b) Some * c) None of: 1. Certified copies of the priority 2. Certified copies of the priority 3. Copies of the certified copies application from the Internationsee the attached detailed Office actions	or documents have be or documents have be sof the priority docum onal Bureau (PCT Ru	en received. en received in Appli nents have been recule 17.2(a)).	ication No eived in this National S	Stage			
Attachmei	nt(s)							
1) 🛛 Noti	ce of References Cited (PTO-892)			mary (PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 5) Notice of Informal Patent Application (PTO-152)								
	mation Disclosure Statement(s) (PTO-1449 c er No(s)/Mail Date	or P10/28/08)	6) Other:	na, r atom Application (r 10	,			

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DETAILED ACTION

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.
- 3. Resolving the level of ordinary skill in the pertinent art.
- 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 1-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hasegawa et al. (US 6414741) in view of Sekiguchi (US 2004/0046909).

With respect to claims 1 and 12: Hasegawa et al. disclose a system of manufacturing a liquid crystal display comprising: a panel manufacturing unit for manufacturing a liquid crystal panel assembly including a thin film transistor (TFT) (Fig. 1, element 12) and a liquid crystal layer interposed between the TFT array panel and the opposing array panel (Column 4, lines 22-27); a printed circuit film bonding unit (Fig. 1, element 22) for bonding a printed circuit film on the panel assembly; and an inspection unit (Fig. 9, element 104) for inspecting the bonding of the printed circuit film on the panel assembly. Moreover, Hasegawa et al. disclose a method of

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manufacturing a liquid crystal display comprising: manufacturing a liquid crystal panel assembly; bonding a printed circuit film on the panel assembly; inspecting the bonding of the printed circuit film on the panel assembly; and bonding a wire board to the printed circuit film (Column 4, lines 22-42).

However, Hasegawa et al. fail to specifically disclose that the opposing array substrate is of a color filter array panel and that the wire board is specifically a printed circuit board (PCB).

Sekiguchi, on the other hand, discloses a liquid crystal display panel comprising a color filter array panel (Paragraph 0137). Furthermore, Sekiguchi discloses the use of a printed circuit board (PCB) bonding unit for bonding a PCB to the printed circuit film (Paragraph 0144).

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to manufacture a liquid crystal panel with a color filter array panel and bonding the printed circuit film to a printed circuit board as taught by Sekiguchi with the system and method of manufacturing of the liquid crystal panel taught by Hasegawa et al., since Sekiguchi teaches that the use of PCB enables the application of signals to the driving ICs of the display panel (Paragraph 0144) and that the color filter array panel provides coloring to the display panel.

As to claim 2: Hasegawa et al. disclose that the printed circuit film comprises a tape carrier package (Column 4, line 38).

As to claim 3: Hasegawa et al. disclose that the inspection unit comprises a CCD camera (Fig. 9, element 104).

As to claims 4-6: Hasegawa et al. disclose that the printed circuit film bonding unit bonds the printed circuit film on the panel assembly with an anisotropic conductive film (ACF)

by compression (Column 4, lines 48-52), wherein the ACF comprises an adhesive containing a plurality of conductive particles (Column 7, line 63).

As to claim 7: Hasegawa et al. disclose that the inspection unit detects dents generated by the compression (Column 7, lines 56-67; wherein the shape of the conductive particles post compression along the substrate face is observed).

As to claim 8: Hasegawa et al. disclose that the inspection unit detects alignment of the printed circuit film with the panel assembly (Column 6, lines 56-67).

As to claim 9: Hasegawa et al. disclose that the bonding inspection unit is incorporated into the printed circuit film bonding unit (Column 6, lines 56-67; Fig. 7, elements 114 and 117; wherein the inspection unit comprises of the dummy lead wires and the branch wires).

As to claims 10 and 11: Hasegawa et al. disclose that the bonding inspection unit comprises two sub-units for inspection. The dummy lead wires, which are incorporated into the printed circuit film bonding unit for before bonding of the wire board inspection (Column 6, lines 56-67), and the aligning marks, which are incorporated into the wire board bonding unit for post bonding of the wire board inspection (Column 8, lines 45-54).

As to claims 13-15: Hasegawa et al. disclose that the inspection is performed both before and after bonding of the wire board (Column 6, lines 56-67; Column 8, lines 45-54).

As to claim 16: Hasegawa et al. disclose that the printed circuit film comprises a tape carrier package (Column 4, line 38).

As to claim 17: Hasegawa et al. disclose that the inspection unit comprises a CCD camera (Fig. 9, element 104).

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As to claim 18: Hasegawa et al. disclose that the printed circuit film bonding unit bonds the printed circuit film on the panel assembly with an anisotropic conductive film (ACF) (Column 4, lines 48-52) containing a plurality of conductive particles (Column 7, line 63).

As to claims 19 and 20: Hasegawa et al. disclose that the bonding of the printed circuit film is performed by thermo compression (Column 7, lines 43-49), and that the inspection detects dents generated by the thermo compression (Column 7, lines 56-67; wherein the shape of the conductive particles post compression along the substrate face is observed).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Wen-Ying P. Chen whose telephone number is (571)272-8444. The examiner can normally be reached on 8:00-5:00 M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert Kim can be reached on (571)272-2293. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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Examiner Art Unit 2871

wpc

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